

| | | | | | | | |
|---|--|--|--|--|--|--|--|
| FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) | | | | ATTY DOCKET NO. 00862.022499 | | APPLICATION NO. Not Yet Assigned | |
| | | | | APPLICANT Takao Yonehara, et al. | | | |
| | | | | FILING DATE Currently herewith | | GROUP Not Yet Assigned | |

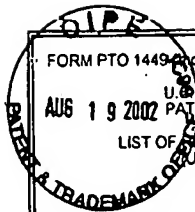
| U.S. PATENT DOCUMENTS | | | | | | | |
|--------------------------|-----------------|----------|--------------------|--|--|--|--|
| EXAMINER INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE | |
| TN | 5,206,749 | 4/27/93 | Zavracky et al. | 359 | 59 | <div style="border-left: 2px solid black; border-right: 2px solid black; height: 100px; width: 100%;"></div> | |
| | 5,256,562 | 10/26/93 | Vu et al. | 437 | 86 | | |
| | 5,811,348 | 9/22/98 | Matsushita, et al. | 438 | 455 | | |
| | 6,107,213 | 8/22/00 | Tayanaka, et al. | 438 | 762 | | |
| | 5,985,742 | 11/16/99 | Henley, et al. | 438 | 515 | | |
| TN | 5,856,229 | 1/5/99 | Sakaguchi, et al. | 438 | 406 | | |
| FOREIGN PATENT DOCUMENTS | | | | | | | |
| | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION YES/NO/ OR ABSTRACT | |
| TN | 9-312349 | 12/2/97 | Japan | <div style="border-left: 2px solid black; border-right: 2px solid black; height: 100px; width: 100%;"></div> | <div style="border-left: 2px solid black; border-right: 2px solid black; height: 100px; width: 100%;"></div> | Abstract | |
| TN | 886 300 | 12/23/98 | EP | | | <div style="border-left: 2px solid black; border-right: 2px solid black; height: 100px; width: 100%;"></div> | |
| | | | | | | | |
| | | | | | | | |
| | | | | | | | |
| | | | | | | | |

| OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.) | | |
|--|--|--|
| | | |
| | | |
| | | |
| | | |

| | |
|-----------------------------|-------------------------------|
| EXAMINER <i>[Signature]</i> | DATE CONSIDERED 3/4/04 |
|-----------------------------|-------------------------------|

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 1



FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

AUG 19 2002

LIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)ATTY DOCKET NO.
00862.022499APPLICATION NO.
10/059,171

APPLICANT

TAKAO YONEHARA, et al.

FILING DATE

January 31, 2002

GROUP

2871

U.S. PATENT DOCUMENTS

| *EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|----------------------|--|--------------------|------------|-------------------|-------|----------|-------------------------------|
| TW | | 6,190,937 | 02/20/2001 | Nauagawa, et al. | 438 | 67 | |
| | | 6,222,513 | 03/10/1998 | Howard, et al. | 345 | 84 | |
| | | 6,258,698 | 07/10/2001 | Iwasaki, et al. | 438 | 455 | |
| | | 6,306,729 | 10/23/2001 | Sauaguchi, et al. | 438 | 458 | |
| | | 6,331,208 | 12/18/2001 | Nishida, et al. | 117 | 89 | |
| | | 6,342,433 | 01/29/2002 | Ohmi, et al. | 438 | 455 | |
| TW | | 6,382,292 | 05/07/2002 | Ohmi, et al. | 156 | 584 | |

FOREIGN PATENT DOCUMENTS

| | | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION YES/NO/ OR ABSTRACT |
|----|----|--------------------|------------|---------|-------|----------|---------------------------------------|
| TW | EP | 1 122 794 | 08/08/2001 | Europe | | | |
| | EP | 858 110 | 08/12/1998 | Europe | | | |
| | EP | 849 788 | 06/24/1998 | Europe | | | |
| TW | JP | 11-316397 | 11/16/1999 | Japan | G02F | | Abstract |
| | | | | | | | |

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

| | | |
|----|--|---|
| TW | | Shimoda, T., et al: "Surface Free Technology By Laser Annealing (SUFTLA)" International Electron Devices Meeting 1999. IEDM. Technical Digest. Washington, DC, Dec. 5-8, 1999, New York, NY: IEEE, US, Aug. 1, 1999 (1999-08-01), pages 289-292, XP000933199 ISBN: 0-7803-5411-7. |
| | | |
| | | |

EXAMINER

DATE CONSIDERED

3/4/04

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 1

| | | | | | | | |
|--|--|--|--|---|--|----------------------------|--|
| FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | | | ATTY DOCKET NO. 00862.022499. | | APPLICATION NO. 10/059,171 | |
| LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) | | | | APPLICANT TAKAO YONEHARA, et al. | | | |
| FILING DATE January 31, 2002 | | | | GROUP 2871 | | | |

| U.S. PATENT DOCUMENTS | | | | | | | |
|-----------------------|--------------------|----------|------------------|-------|----------|--|--|
| OWNER INITIALS | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE | |
| TW | 6,075,280 | 06/13/00 | Yung et al. | 257 | 620 | <div style="position: relative; height: 100px;"> X </div> | |
| | 6,136,668 | 10/24/00 | Tamaki, et al. | 438 | 462 | | |
| | 6,186,384 | 02/13/01 | Sawada | 225 | 2 | | |
| | 6,465,329 | 10/15/02 | Glenn | 438 | 462 | | |
| | 2002/0076904 | 06/20/02 | Imler | 438 | 462 | | |
| TW | 2002/0100941 | 08/01/02 | Yonehara, et al. | 257 | 359 | | |
| | | | | | | | |
| | | | | | | | |

| FOREIGN PATENT DOCUMENTS | | | | | | | |
|--------------------------|------|---------|-------|----------|---------------------------------------|--|--|
| DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION YES/NO/ OR ABSTRACT | | |
| | | | | | | | |
| | | | | | | | |
| | | | | | | | |
| | | | | | | | |
| | | | | | | | |
| | | | | | | | |
| | | | | | | | |

| OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.) | | |
|--|--|--|
| | | |
| | | |
| | | |
| | | |
| | | |

| | |
|----------------------|-------------------------------|
| EXAMINER <i>hant</i> | DATE CONSIDERED 3/4/04 |
|----------------------|-------------------------------|

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.